

Supplementary information

Role of size, alio-/multi-valency and non-stoichiometry in the synthesis of phase-pure high entropy oxide (Co,Cu,Mg,Na,Ni,Zn)O

**Nandhini J. Usharani, Rajat Shringi, Harshil Sanghavi, S. Subramanian² and S.S.
Bhattacharya[#]**

Nano Functional Materials Technology centre, (NFMTC),

Department of Metallurgical and Materials engineering,

²Sophisticated Analytical Instrument Facility,

Indian Institute of Technology Madras, Chennai-600036, India.

[#]ssb@iitm.ac.in

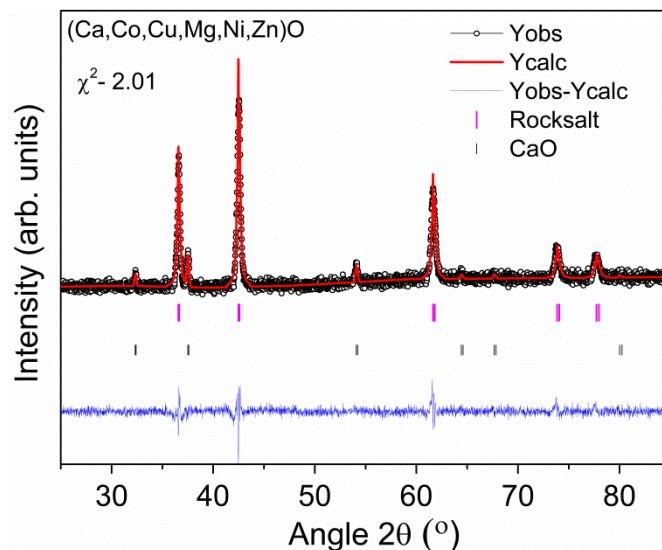


Figure S1 Rietveld refinement of XRD pattern of $(\text{Ca},\text{Co},\text{Cu},\text{Mg},\text{Ni},\text{Zn})\text{O}$ showing the presence of rocksalt structure and CaO

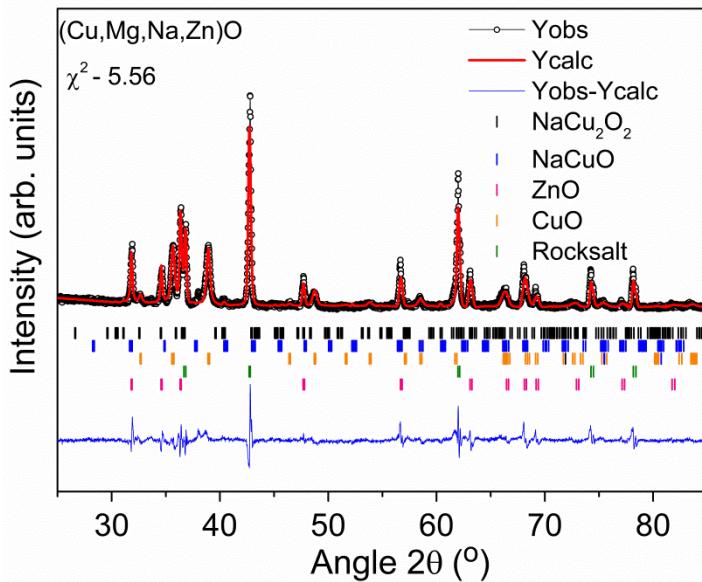


Figure S2 Rietveld refinement of the XRD pattern of $(\text{Cu},\text{Mg},\text{Na},\text{Zn})\text{O}$ showing the presence of multiple phases (rocksalt – 52%, monoclinic – 26%, hexagonal – 20.17% with some minor amounts of orthorhombic $\text{Na}_2\text{Cu}_2\text{O}_2$ and tetragonal NaCuO)

Table S1 d-spacing obtained from Rietveld refinement of $(\text{Co},\text{Cu},\text{Mg},\text{Ni},\text{Na},\text{Zn})\text{O}$

2-theta (°)	d-spacing (Å)	(hkl)
36.629	2.45133	(-201)
36.703	2.446501	(110)
36.718	2.445596	(001)
42.529	2.123879	(200)
42.665	2.117439	(-111)
61.758	1.500846	(-311)
61.879	1.498212	(111)
61.882	1.498152	(-202)
61.964	1.49636	(020)
73.9	1.28141	(-401)
74.002	1.279899	(310)
74.066	1.278951	(201)
74.1	1.278448	(-312)
74.184	1.277205	(-221)
74.21	1.276819	(-112)
74.239	1.276392	(021)
77.873	1.225665	(-402)
78.056	1.223251	(220)
78.09	1.222798	(002)

Table S2 Occupancy of cations from Rietveld refinement of (Co,Cu,Mg,Na,Ni,Zn)O

Cation	X	Y	Z	occupancy
O	0	0.5	0.5	0.9326
Co	0	0	0	0.1666
Cu	0	0	0	0.1666
Mg	0	0	0	0.1666
Na	0	0	0	0.1666
Ni	0	0	0	0.1666
Zn	0	0	0	0.1666

Table S3 Composition from energy dispersive spectroscopy

Composition	Co (%)	Cu (%)	Na (%)	Ni (%)	Mg (%)	Zn (%)
Na-TMO	8.3	6.5	9.6	8.0	10.0	7.6
ME-TMO	11.3	9.7	-	10.3	8.4	10.3

Table S4 Assignment of the peaks obtained in X-ray photoelectron spectroscopy

Cation	Oxidation state	Assigned to	Position (eV)
Ni	+3	2p _{3/2}	856.39
		2p _{3/2} satellite	862.45
		2p _{1/2}	873.52
	+2	2p _{3/2}	855.03
		2p _{3/2} satellite	860.31
		2p _{1/2}	871.86
		2p _{1/2} satellite	877.65
Co	0	2p	852.86
	+3	2p _{3/2}	779.73
		2p _{3/2} satellite	788.82
		2p _{1/2}	796.26
	+2	2p _{1/2} satellite	803.27
		2p _{3/2}	781.72
		2p _{3/2} satellite	786.04
		2p _{1/2}	794.14
Cu	+2	2p _{1/2} satellite	800.48
		2p _{3/2}	933.03
		2p _{3/2} satellite	938.68
		2p _{1/2}	954.23
	+1	2p _{1/2} satellite	960.65
		2p _{3/2}	932.46
Na	+1	2p _{1/2}	952.03
	+1	1s	1070.89
Zn	+2	2p _{3/2}	1020.36
		2p _{3/2} satellite	1035.04
	+2	2p _{1/2}	1043.37
Mg	+2	2p	49.54
O	O ²⁻		530.05
	O ¹⁻	1s	531.80
	Adsorbed		533.70

Table S5 Binding energies of Cu used for assignment of oxidation states

Compound	Oxidation state	2p _{3/2} (eV)	2p _{1/2} (eV)	2p _{3/2} S (eV)	2p _{1/2} S (eV)	Ref
Ni doped CuO	Cu ²⁺	933.15	953.5	941.8	961.5	¹
Cu ₂ O	Cu ¹⁺	932.0	951.8	NA ^a	NA ^a	²
CuO	Cu ²⁺	933.8	-	-	-	³
	Cu ¹⁺	932.8	-	-	-	
CuO	Cu ²⁺	933.3	953.2	942	962	⁴
CuO	Cu ²⁺	933.8	-	-	-	⁵
	Cu ¹⁺	932.6	-	-	-	
CuO	Cu ²⁺	933.6	-	-	-	⁶
	Cu ¹⁺	932.4	-	-	-	
CuO	Cu ²⁺	933.9	953.9	-	-	⁷
	Cu ¹⁺	932.3	952.2	-	-	
(Co,Cu,Mg,Na,Ni,Zn)O	Cu ²⁺	933.03	954.23	938.68	960.65	Present work
	Cu ¹⁺	932.46	952.03	-	-	

^aValues mentioned as *NA is respective peak does not exist for the particular oxidation state.

Table S6 Binding energies of Zn used for assignment of oxidation states

Compound	Oxidation state	2p _{3/2} (eV)	2p _{1/2} (eV)	Ref
ZnO	Zn ²⁺	1021.8	1044.9	⁸
ZnO	Zn ²⁺	1022.40	-	⁹
ZnO	Zn ²⁺	1021.5	-	¹⁰
ZnO	Zn ²⁺	1022	1045	¹¹
(Co,Cu,Mg,Na,Ni,Zn)O	Zn ²⁺	1020.36	1043.37	Present work

Table S7 Binding energies of O used for assignment of position of O in the lattice

Compound	O lattice (eV)	O deficiency (eV)	O adsorbed (eV)	Ref
ZnO	530.2	531.8	533.4	¹²
Al doped ZnO	530.15	531.25	532.40	⁹
ZnO	530.2	531.4	532.6	¹³
MgO	530.3-530.6	532.5-533.5	-	¹⁴
Co _{1-x} Na _x O	529.9	-	531.4 eV.	¹⁵
CoO	529.5	530.8	533.0	¹⁶
(Co,Cu,Mg,Na,Ni,Zn)O	530.05	531.80	533.7	Present work

Table S8 Binding energies of Mg used for assignment of oxidation states

Compound	Oxidation state	2p (eV)	Ref
MgO	Mg ²⁺	50.8	¹⁴
MgO	Mg ²⁺	49.3	¹⁷
MgO	Mg ²⁺	49.8	¹⁸
(Co,Cu,Mg,Na,Ni,Zn)O	Mg ²⁺	49.54	Present work

Table S9 Binding energies of Na used for assignment of oxidation states

Compounds	Oxidation state	2s (eV)	Ref
Na _x CoO ₂	Na ¹⁺	1071.71	¹⁹
Na doped ZnO	Na ¹⁺	1073.2	²⁰
Co _{1-x} Na _x O	Na ¹⁺	1072	¹⁵
Na doped NiO	Na ¹⁺	1072.8	²¹
(Co,Cu,Mg,Na,Ni,Zn)O	Na ¹⁺	1070.89	Present work

Table S10 Binding energies of Ni used for assignment of oxidation states

Compounds	Oxidation state	2p _{3/2} (eV)	2p _{1/2} (eV)	2P _{3/2} S (eV)	2P _{1/2} S (eV)	Ref
NiO	Ni ²⁺	854.1	871.6	861.2	878.8/881.5	²²
Co-doped NiO	Ni ²⁺	854.3	874.0			²³
Na ₂ Ni ₂ TeO ₆	Ni ²⁺	854.2	-	-	-	²⁴
	Ni ³⁺	855.4	-	-	-	
Ni ₂ O ₃ .6H ₂ O	Ni ³⁺	855.1	872.7	860.9	879.3	²⁵
Na doped NiO	Ni ²⁺	854.5	872.7	861.7	880.8	²¹
	Ni ³⁺	856.3	-	-	-	
NiO	Ni ²⁺	853.5	872.8	861.3	879.1	²⁶
	Ni ³⁺	855.5	-	-	-	
(Co,Cu,Mg,Na,Ni,Zn)O	Ni ²⁺	855.03	871.86	860.31	877.65	Present work
	Ni ³⁺	856.39	873.52	862.45	-	

Table S11 Binding energies of Co used for assignment of oxidation states

Compounds	Oxidation state	2p _{3/2} (eV)	2p _{1/2} (eV)	2p _{3/2} S (eV)	2p _{1/2} S (eV)	Ref
Co-doped NiO	Co ²⁺	780	795.5	-	-	²³
CoO	Co ²⁺	780.5	796.3	786.4	803.0	¹⁶
Co ₃ O ₄	Co ³⁺	779.6	794.5	789.5	804.5	¹⁶
CoO	Co ²⁺	780.6	796.8	-	-	²⁷
Co ₃ O ₄	Co ³⁺	779.6	-	787.9	803.8	²⁸
(Co,Cu,Mg,Na,Ni,Zn)O	Co ²⁺	781.72	794.14	786.04	800.48	Present work
	Co ³⁺	779.73	796.26	788.82	803.27	

Table S12 Ionic radii difference of each cation as compared to Ni²⁺

Element	Oxidation state	Ionic radii (pm)	Co-ordination number	Ionic radii difference compared to Ni ²⁺
Co	+2	745	+6	7.9 %
Cu	+2	73	+6	5.7 %
Mg	+2	72	+6	4.3 %
Na	+1	102	+6	47.8 %
Ni	+2	69	+6	-
Zn	+2	74	+6	7.2 %

References

- 1 S. Dolai, S. N. Sarangi, S. Hussain, R. Bhar and A. K. Pal, *J. Magn. Magn. Mater.*, 2019, **479**, 59–66.
- 2 L. Li, L. Xu, W. Shi and J. Guan, *Int. J. Hydrogen Energy*, 2013, **38**, 816–822.
- 3 C. C. Chusuei, M. A. Brookshier and D. W. Goodman, *Langmuir*, 1999, **15**, 2806–2808.
- 4 A. I. Stadnichenko, A. M. Sorokin and A. I. Boronin, *J. Struct. Chem.*, 2008, **49**, 341–347.
- 5 G. Panzner, B. Egert and H. P. Schmidt, *Surf. Sci.*, 1985, **151**, 400–408.
- 6 S. Poulston, P. M. Parlett, P. Stone and M. Bowker, *Surf. Interface Anal.*, 1996, **24**, 811–820.
- 7 D. Barreca, A. Gasparotto and E. Tondello, *Surf. Sci. Spectra*, 2007, **14**, 41–51.
- 8 Z. Zhang, C. Shao, X. Li, C. Wang, M. Zhang and Y. Liu, *ACS Appl. Mater. Interfaces*, 2010, **2**, 2915–2923.
- 9 M. Chen, X. Wang, Y. H. Yu, Z. L. Pei, X. D. Bai, C. Sun, R. F. Huang and L. S. Wen, *Appl. Surf. Sci.*, 2000, **158**, 134–140.
- 10 L. Armelao, D. Barreca, G. Bottaro, A. Gasparotto, D. Leonarduzzi, C. Maragno and E. Tondello, *Surf. Sci. Spectra*, 2006, **13**, 9–16.
- 11 X. Q. Wei, B. Y. Man, M. Liu, C. S. Xue, H. Z. Zhuang and C. Yang, *Phys. B Condens. Matter*, 2007, **388**, 145–152.
- 12 J. Wang, Z. Wang, B. Huang, Y. Ma, Y. Liu, X. Qin, X. Zhang and Y. Dai, *ACS Appl. Mater. Interfaces*, 2012, **4**, 4024–4030.
- 13 P. T. Hsieh, Y. C. Chen, K. S. Kao and C. M. Wang, *Appl. Phys. A Mater. Sci. Process.*, 2008, **90**, 317–321.
- 14 J. S. Corneille, J. W. He and D. W. Goodman, *Surf. Sci.*, 1994, **306**, 269–278.
- 15 C. Chen, F. Delorme, F. Schoenstein, M. Zaghroui, D. Flahaut, J. Allouche and F. Giovannelli, *J. Eur. Ceram. Soc.*, 2019, **39**, 346–351.
- 16 T. J. Chuang, C. R. Brundle and D. W. Rice, *Surf. Sci.*, 1976, **59**, 413–429.

- 17 F. Khairallah and A. Glisenti, *Surf. Sci. Spectra*, 2006, **13**, 58–71.
- 18 C. Ruby, B. Humbert and J. Fusy, *Surf. Interface Anal.*, 2000, **29**, 377–380.
- 19 H. Sang, G. Ho, D. Hyun and S. Ihl, *Curr. Appl. Phys.*, 2015, **15**, 412–416.
- 20 Z. Wu, Y. Li, L. Gao, S. Wang and G. Fu, *Dalt. Trans.*, 2016, **45**, 11145.
- 21 Y. Rama, K. Lee, C. Park, S. Kun, H. Jae, D. Yang and S. Seo, *Thin Solid Films*, 2015, **591**, 255–260.
- 22 A. N. Mansour, *Surf. Sci. Spectra*, 1994, **3**, 231–238.
- 23 Z. Zheng, L. Huang, Y. Zhou, X. Hu and X. Ni, *Solid State Sci.*, 2009, **11**, 1439–1443.
- 24 A. Gupta, C. Buddie Mullins and J. B. Goodenough, *J. Power Sources*, 2013, **243**, 817–821.
- 25 A. N. Mansour and C. A. Melendres, *Surf. Sci. Spectra*, 1994, **3**, 263–270.
- 26 X. Geng, D. Lahem, C. Zhang, C. Li, M. Olivier and M. Debliquy, *Ceram. Int.*, 2019, **45**, 4253–4261.
- 27 M. Hassel and H.-J. Freund, *Surf. Sci. Spectra*, 1996, **4**, 273–278.
- 28 G. A. Carson, M. H. Nassir and M. A. Langell, *J. Vac. Sci. Technol. A Vacuum, Surfaces, Film.*, 1996, **14**, 1637–1642.